



OIML/UNIDO Seminar on D 1 (Elements for a Law on Metrology)

Why and how to legislate on metrology?

Tuesday 23 October 2007 (afternoon)

Draft Agenda

- 14:00 **Opening**
Eberhard Seiler, Chairman of the OIML Permanent Working Group on Developing Countries
- 14:15 **Presentation of D 1, how to use it**
Jean-François Magana, BIML Director
- 14:45 **The Development of China Metrology law**
Xuan Xiang, Director General of the Metrology Department AQSIQ (China)
- 15:15 **Development of a new law in Vietnam**
Manfred Kochsiek
- 15.45 Coffee Break
- 16:15 **Issues encountered in metrology legislation in D.R. Congo**
Kanama Viki Mbuya, Director of Quality, Metrology & Standardization (D.R. Congo)
- 16.45 **Legislation on metrology in Developing Countries**
Otto Loesener, UNIDO
- 17:15 **Legislation on metrology in Developing Countries**
John Birch
- 17:45 Discussion
- 18:00 Closure